Transaction Information

Tool ID	OPI922
Tool Status	Connected
Location	Dresden, Germany
Wafer Size	300 mm
Fab Section	Defect Detection
Tool Available Date	2025-02-01

General Product Information

Vendor Supplier	HSEB
Model	MMT 300
Vintage	2007
Serial No	004/01 (2007)
Asset Description	OPI922-T MMT 300
Software Version	4.32.4/10.1.04
CIM	SECS/GEM
Process	Wafer Inspection Tool

Hardware Configuration (Fab)

System Type	Description	Quantity	Status
Main System	microscope station	1	OK
Options System			

Hardware Configuration (Subfab / Auxilliary Units)

Description	Quantity	Status
NONE		

Missing/Faulty Parts / Accesorries List

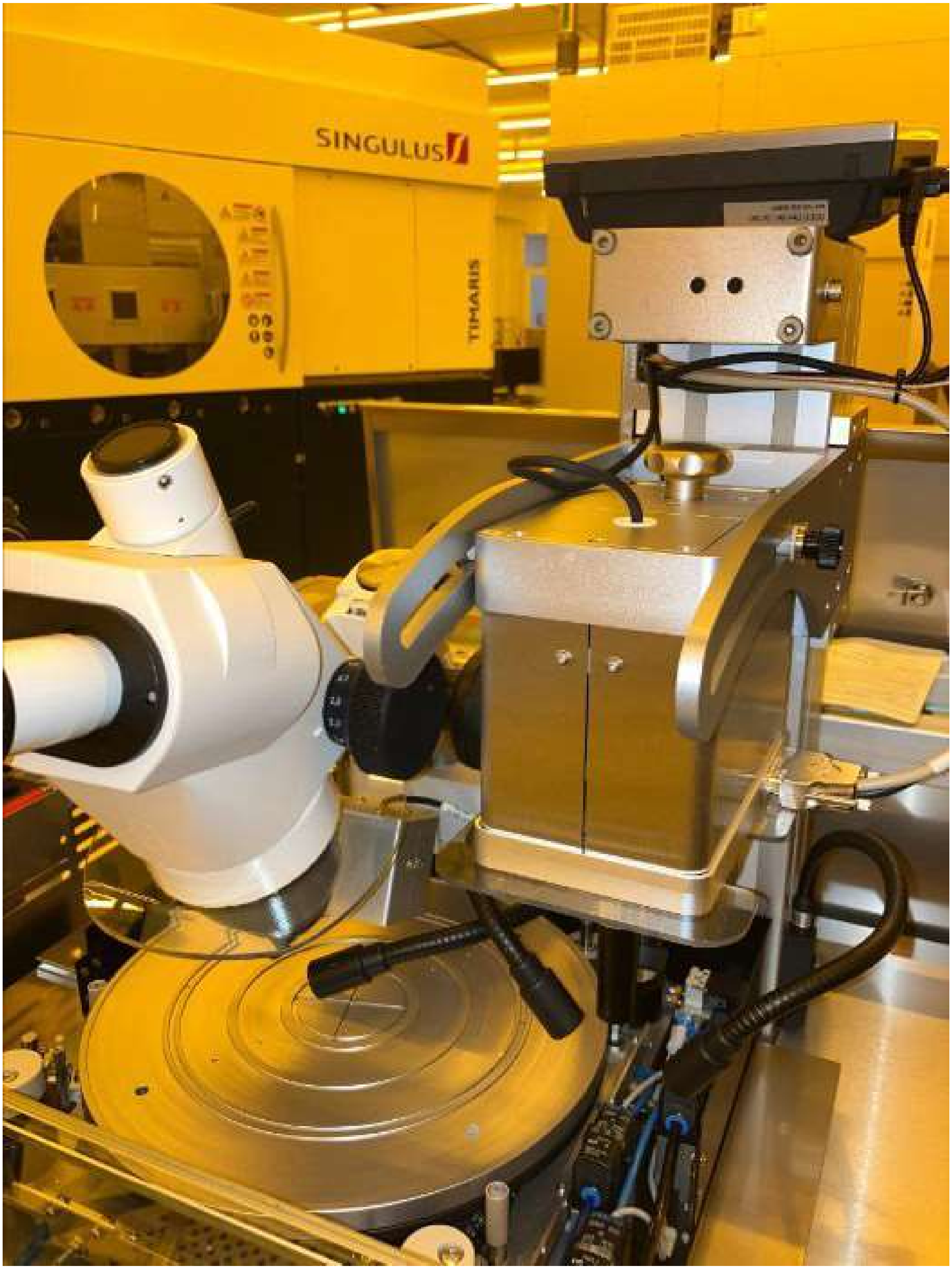
Description	Quantity
NONE	

Tool Pictures

General	mainframe and inspection module

General	mainframe and inspection module

General	mainframe and inspection module



General	mainframe and inspection module

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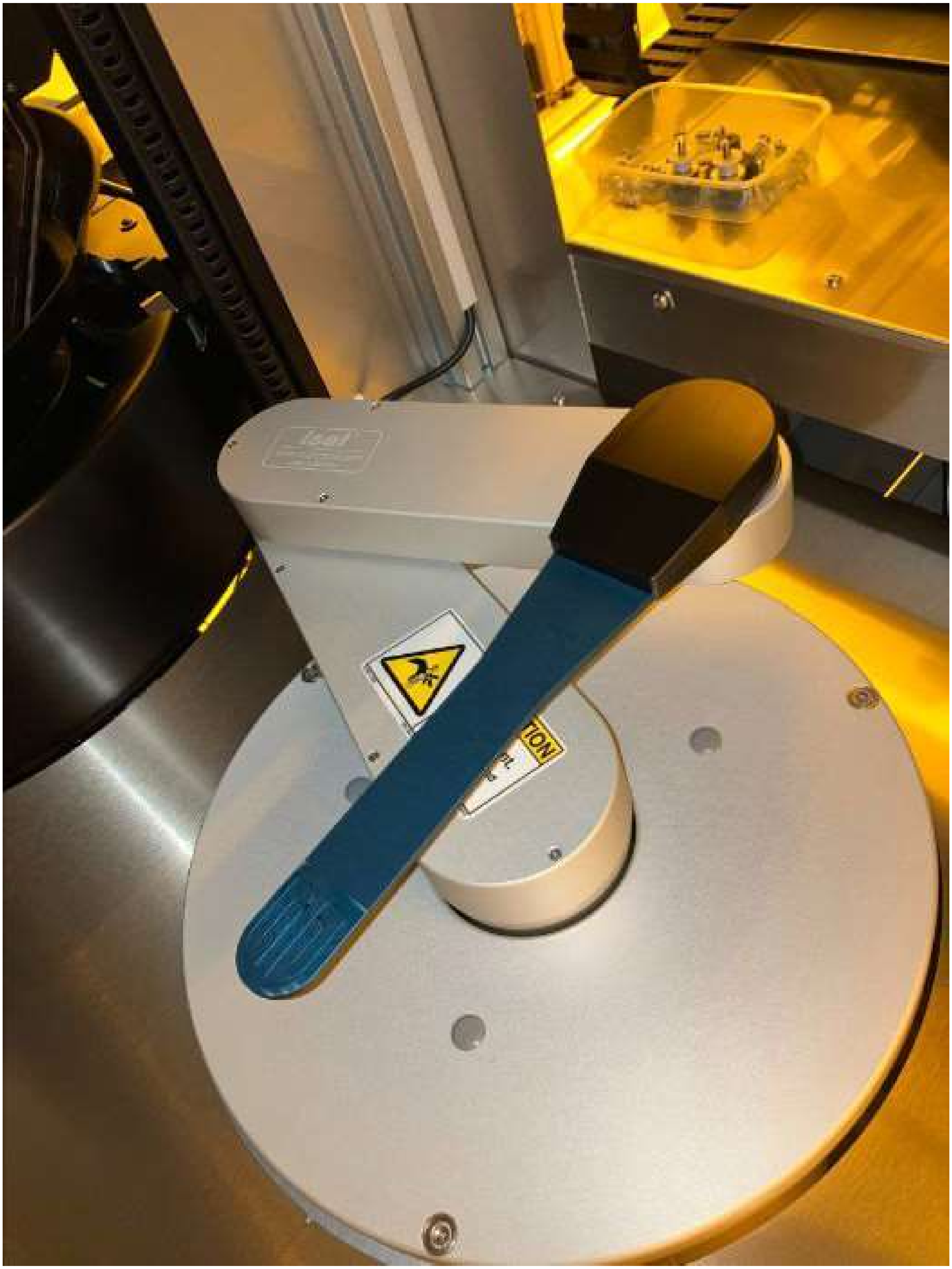

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Manufacture Serial	Serial Number Plate

HSEB Dresden GmbH

MMT 300
VERSION 02 (V2)
Cat. No. 2025-20011
Ser. No. 004/01 (2007)
1/N/PE 115/230 V AC < 800 VA
50 - 60 Hz 10 A
025.02-7100.000F-Sp.00